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ICS 31.080.01
CCS L55

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 20938-2005

Microwave circuits. Measuring methods for frequency converters

微波电路变频测试方法

(English Translation)

Issued on: January 18, 2006 **Implemented on: June 1, 2006**

Issued by: Ministry of Industry and Information Technology

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1 Foreword

SJ 20938-2005 was issued by Ministry of Industry and Information Technology on 18 January 2006 and has been in force since 1 June 2006.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 17 pages in English translation.

2 Scope Preview

This standard specifies the microwave circuit upconverter, down converter electrical parameters of the test method.

SJ 20938-2005 falls under ICS 31.080.01, in the field of electronics.

This catalogue holds 133 other SJ standards in that field.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

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3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 17 pages (approximate)

Chinese original: about 25,284 characters

4 Related standards

Standards on related subjects:

GB/T 46280.2-2025 - Specification for chiplet interconnection interface - Part 2: Protocol layer technical requirements

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

SJ 21473.7-2021 - Methods of measuring electromagnetic immunity of military integrated circuits - Part 7: Measurement of pulse immunity - non-synchronous transient injection method

SJ 21473.6-2021 - Methods of measuring electromagnetic immunity of military integrated circuits - Part 6: Impulse immunity measurement - Synchronous transient injection method

5 Classification and status

International classification (ICS): 31.080.01

Chinese Standard Classification (CCS): L 55

Prefix SJ: mandatory standard.

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